Ask for performance - ask for the new D 5000 x-ray diffractometer



Complete set of attachments for specific applications:

- Eulerian cradle for texture.
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- Programmable sample rotation.

Available with computer controlled variable aperture slits in incident and diffracted beam paths to control divergence and reduce background.

For maximum performance in your lab, Siemens has engineered a new generation of x-ray diffractometer designed to meet your requirements. The D 5000 features a new goniometer design manufactured to the strictest tolerances. Complete with application specific attachments and advanced software routines, the D 5000 has the precision and flexibility to outperform other systems in every x-ray application.

Your Solution is Siemens

In USA & Canada contact Siemens Analytical X-Ray Instruments, Inc., a joint venture of Siemens & Nicolet.
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